


<b>Search Notes</b> 	<b>Application/Control No.</b> 10763817	<b>Applicant(s)/Patent Under Reexamination</b> TANAKA, MIKIHIRO
	<b>Examiner</b> NAM HUYNH	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
455	450, 451, 452.2, 453, 454	3/14/08	NTH
370	342, 348	3/14/08	NTH

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST search notes.	3/14/08	NTH
Received search help from 370 Examiner Ngo Nguyen	1/15/2009	NTH
See EAST search notes.	1/16/2009	NTH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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